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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Date: June 1, 1998

Beaman et al.

Group Art Unit:

Serial No.

Examiner:

Filed: (Herewith)

Docket No.: YO993-028AX

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND
METHODS OF USE THEREOF

The Commissioner of Patents and Trademarks
Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

IN THE CLAIMS

Cancel claims 1-5, 20 and 21.

22. (Amended) An electronic device probe for probing an electronic device comprising:

a first space transformer having a surface;

said surface having a first plurality of contact locations;

a plurality of elongated electrical conductors each having a
protuberance at one end thereof;

said each of said protuberance of each of said plurality of elongated conductors is

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35 USC 133

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